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<ul> <li>State-of-the-Art BiCMOS Design Significantly Reduces I<sub>CC</sub></li> </ul>	SN54BCT374 J OR W PACKAGE SN74BCT374 DB OR DW OR N PACKAGE (TOP VIEW)				
<ul> <li>Full Parallel Access for Loading</li> </ul>					
<ul> <li>Buffered Control Inputs</li> </ul>					
• 3-State True Outputs Drive Bus Lines	1Q [ <mark>]</mark> 2 19 <mark>]</mark> 8Q				
or Buffer Memory Address Registers	1D 🚺 3 18 🗍 8D				
• ESD Protection Exceeds 2000 V	2D 🛛 4 17 🗍 7D				
Per MIL-Std-883C, Method 3015	2Q 🛛 5 16 🗍 7Q				
Package Options Include Plastic	3Q 🚺 6 🛛 15 🗍 6Q				
Small-Outline (DW) and Shrink	3D 🚺 7 14 🗍 6D				
Small-Outline (DB) Packages, Ceramic Chip	4D 🚺 8 13 🗍 5D				
Carriers (FK) and Flatpacks (W), and	4Q [] 9 12 ]] 5Q				
Standard Plastic and Ceramic 300-mil DIPs					

## SN54BCT374 . . . FK PACKAGE

(TOP VIEW)

€ € |8 <sup>2</sup> 2 8 2 1 20 19 2D 8D Δ 18 2Q 7D 5 17 3Q Π6 16 7Q 3D 6Q ٦ 7 15 4D 6D 8 14 9 10 11 12 13 GND 50 50

description

(J, N)

These 8-bit flip-flops feature 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. They are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

The eight flip-flops of the 'BCT374 are edge-triggered D-type flip-flops. On the positive transition of the clock (CLK) input, the Q outputs are set to the logic levels that were set up at the data (D) inputs.

A buffered output-enable ( $\overline{OE}$ ) input can be used to place the eight outputs in either a normal logic state (high or low) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and the increased drive provide the capability to drive bus lines without need for interface or pullup components. The output-enable ( $\overline{OE}$ ) input does not affect internal operations of the flip-flop. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The SN54BCT374 is characterized for operation over the full military temperature range of  $-55^{\circ}$ C to  $125^{\circ}$ C. The SN74BCT374 is characterized for operation from 0°C to 70°C.

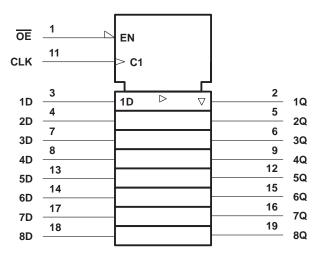
(each flip-flop)									
	INPUTS	OUTPUT							
OE	CLK	D	Q						
L	$\uparrow$	Н	Н						
L	$\uparrow$	L	L						
L	H or L	Х	Q <sub>0</sub>						
н	Х	Х	z						

FUNCTION TABLE

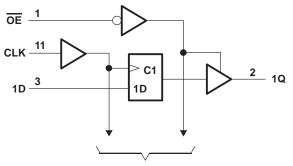
PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

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### logic symbol<sup>†</sup>



logic diagram (positive logic)



To Seven Other Channels

<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>‡</sup>

Supply voltage range, V <sub>CC</sub>		– 0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)		
Voltage range applied to any output in	the disabled or power-off state, V	O 0.5 V to 5.5 V
Voltage range applied to any output in	the high state, VO	-0.5 V to V <sub>CC</sub>
Input clamp current		
Current into any output in the low state	e: SN54BCT374	
		128 mA
Operating free-air temperature range:	SN54BCT374	– 55°C to 125°C
	SN74BCT374	0°C to 70°C
Storage temperature range		– 65°C to 150°C

<sup>‡</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

### recommended operating conditions

		SN54BCT374		SN74BCT374			UNIT	
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2			2			V
VIL	Low-level input voltage			0.8			0.8	V
IIK	Input clamp current			-18			-18	mA
IOH	High-level output current			-12			-15	mA
IOL	Low-level output current			48			64	mA
TA	Operating free-air temperature	-55		125	0		70	°C



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## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		SN	54BCT3	74	SN	UNIT		
PARAMETER			MIN	түр†	MAX	MIN	түр†	MAX	UNIT
VIK	V <sub>CC</sub> = 4.5 V,	lj = -18 mA			-1.2			-1.2	V
		I <sub>OH</sub> = -3 mA	2.4	3.3		2.4	3.3		
VOH	$V_{CC} = 4.5 V$	$I_{OH} = -12 \text{ mA}$	2	3.2					V
		I <sub>OH</sub> = -15 mA				2	3.1		
Voi	V <sub>CC</sub> = 4.5 V	I <sub>OL</sub> = 48 mA		0.38	0.55				V
VOL	VCC = 4.5 V	I <sub>OL</sub> = 64 mA					0.42	0.55	v
lj	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 5.5 V			0.4			0.4	mA
Iн	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 2.7 V			20			20	μΑ
١ <sub>IL</sub>	V <sub>CC</sub> = 5.5 V,	$V_{I} = 0.5 V$			-0.6			-0.6	mA
los‡	V <sub>CC</sub> = 5.5 V,	$V_{O} = 0$	-100		-225	-100		-225	mA
IOZH	V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 2.7 V			50			50	μΑ
IOZL	V <sub>CC</sub> = 5.5 V,	$V_{O} = 0.5 V$			-50			-50	μΑ
ICCL	V <sub>CC</sub> = 5.5 V			37	60		37	60	mA
ІССН	V <sub>CC</sub> = 5.5 V			2	5		2	5	mA
Iccz	V <sub>CC</sub> = 5.5 V			5	8		5	8	mA
Ci	V <sub>CC</sub> = 5 V,	$V_{I} = 2.5 \text{ V or } 0.5 \text{ V}$		6			6		pF
Co	V <sub>CC</sub> = 5 V,	$V_{O} = 2.5 \text{ V or } 0.5 \text{ V}$		10			10		pF

<sup>†</sup> All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

<sup>‡</sup>Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

# timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

		V <sub>CC</sub> =	V <sub>CC</sub> = 5 V, T <sub>A</sub> = 25°C		SN54BCT374		SN74BCT374		
			MIN	MAX	MIN	MAX	MIN	MAX	
fclock	Clock frequency			70		70		70	MHz
tw	Pulse duration	CLK high	7		8		7		ns
t <sub>su</sub>	Setup time before CLK↑	Data high or low	6.5		6.5		6.5		ns
t <sub>h</sub>	Hold time after CLK↑	Data high or low	0		0		0		ns



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#### switching characteristics (see Note 2)

PARAMETER	FROM (INPUT)			CC = 5 V = 50 pl 1 = 500 9 2 = 500 9 A = 25°C	F, .2, .2,	C R R T	L = 50 p 1 = 500 2 = 500 A = MIN	Ω, Ω, to MAX†		UNIT
			'	′BCT374		SN54BCT374		SN74BCT374		
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
fmax			70			70		70		MHz
<sup>t</sup> PLH	CLK	Q	2	7.2	9.1	2	11.6	2	10.6	ns
<sup>t</sup> PHL	OLK	Q	2	7.1	8.8	2	10.6	2	10	115
<sup>t</sup> PZH	OE	Q	1	8.3	10.1	1	12.7	1	12.3	ns
<sup>t</sup> PZL	UE	Q	1	8.6	10.6	1	13	1	12.7	115
<sup>t</sup> PHZ	OE	Q	1	4.7	6.3	1	7.1	1	6.8	ns
<sup>t</sup> PLZ		Q	1	4.8	6.3	1	7.5	1	6.8	115

<sup>†</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.



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